



University of Stuttgart



GS-IMTR

Graduate School
Intelligent Methods for Test and Reliability

ADVANTEST®

2nd Annual Graduate School Meeting

Dirk Pflüger, Matthias Sauer

November 11, 2020

Agenda 2nd Annual Graduate School Meeting

Date: 11.11.2020 9am – 5:45pm CET

Time	Title	Presenter
09:00 – 09:30	Opening & Graduate School Status Overview & Advantest University, Long-Term Vision	Matthias Sauer (ADV), Richard Junger (ADV), Dirk Pflüger (U Stuttgart)
09:30 – 10:30	Keynote “The Future of Test (Some Thoughts)”	Matteo Sonza Reorda (Politech. Turino)
10:30 – 10:45	Break	
10:45 – 11:30	Introduction of Research Group Semiconductor Test and Reliability (Hussam Amrouch)	Hussam Amrouch
11:30 – 12:30	Lunch Break	
12:30 – 13:00	P6: Deep learning based variable selection for post-silicon validation	Bin Yang
13:00 – 13:30	P3: Self-Learning Test Case Generation for Post-Silicon Validation	Dirk Pflüger
13:30 – 14:00	P2: Visual Analytics for Post-Silicon Validation	Thomas Ertl, Daniel Weiskopf, Steffen Koch
14:00 – 14:30	AP1: Offline and online dependability management using reconfigurable networks AP2: Dependable Integration of Reconfigurable Scan Networks for Test and Diagnosis AP3: Variation-Aware Test Method to Increase the Reliability of Nano-Scale Devices	Ahmed Atteya, Natalia Lylina, Paria Haghi and Hans-Joachim Wunderlich
14:30 – 15:00	Break	
15:00 – 15:30	P7: Miniaturized Millimeter-Wave RF Interface Module	Ingmar Kallfass
15:30 – 16:00	P4: Secure and Privacy-Preserving Semiconductor Testing	Ralf Küsters
16:00 – 16:30	P5: Automated Generation of System-Level Test Programs for Characterization of Parametric Device Properties	Steffen Becker, Ilia Polian, Steffen Wagner
16:30 – 17:00	P1: Systematic Analysis of System-Level Test Fails	Jens Anders, Ilia Polian
17:00 – 17:30	P8: Software Test Suite Optimization for Complex High Data-Volume SW	Steffen Becker, Andre van Hoorn, Stefan Wagner
17:30 – 17:45	Closing	
17:45 – 18:45	Internal Advisory Board Session	